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Accession number:13046641

Title:Silicon based millimeter wave and THz ICs

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Source title:IEICE Transactions on Electronics

Abbreviated source title:IEICE Trans. Electron. (Japan)

Volume:E95-C

Issue:7

Publication date:July 2012

Pages:1134-40

Language:Japanese

ISSN:0916-8524

CODEN:IELEEEJ

Document type:Journal article (JA)

Publisher:IEICE

Country of publication:Japan

Material Identity Number:FF49-2012-007

Abstract:In this paper, the research advances in silicon based millimeter wave and THz ICs in the State Key Laboratory of Millimeter Waves is reviewed, which consists of millimeter wave amplifiers, mixers, oscillators at Q, V and W and D band based on CMOS technology, and several research approaches of THz passive ICs including cavity and filter structures using SIW-like (Substrate Integrated Waveguide-like) guided wave structures based on CMOS and MEMs process. The design and performance of these components and devices are presented.

Number of references:15

Inspec controlled terms:CMOS integrated circuits - elemental semiconductors - micromechanical devices - silicon - submillimetre wave integrated circuits - substrate integrated waveguides

Uncontrolled terms:silicon based millimeter wave IC - state key laboratory of millimeter waves - millimeter wave amplifiers - millimeter wave mixers - millimeter wave oscillators - CMOS technology - THz passive IC - SIW-like guided wave structures - substrate integrated waveguide-like guided wave structures - MEMs process - Si

Inspec classification codes:B1350H Microwave integrated circuits - B2570D CMOS integrated circuits - B2575D Design and modelling of micromechanical devices - B1310 Waveguides and striplines

Chemical indexing:Si/int Si/el

Treatment:Practical (PRA)

Discipline:Electrical/Electronic engineering (B)

DOI:10.1587/transele.E95.C.1134

Database:Inspec

IPC Code:B81B; H01L27/085; H01P3/00Copyright 2012, The Institution of Engineering and Technology